

<b>Notice of References Cited</b>	Application/Control No. 10/811,976	Applicant(s)/Patent Under Reexamination CHUNG ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0012558	01-2003	Kim et al.	386/97
*	B	US-2001/0029500	10-2001	Tanaka, Masahide	707/3
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